

Search Notes

Application/Control No.

10/541,015

Applicant(s)/Patent under
Reexamination

SCHLEUCHER, HEIKO

Examiner

SANG KIM

Art Unit

3654

SEARCHED

Class	Subclass	Date	Examiner
242	580 579 402 172	8/21/2007	SK
24	600.9	8/21/2007	SK
24	601.2-4	8/21/2007	SK
24	601.7-9	8/21/2007	SK
24	698.1-3	8/21/2007	SK
242	584.1	12-18-07	SIC
242	587.1	12-18-07	SK
updated above	X	12-18-07	SIC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
John Nguyen: 242/402, 172 Dean Kramer: 294/No search	8/14/2007	SK
James Brittain: 24/600.9, 601.2-4, 601.7-9, 698.1-3	8/21/2007	SK
Scott Haugland: 242/ 584.1, 587.1	12-18-07	SIC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
updated above	X	12-18-07	SIC